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PCT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



In re Application of:

PCT

OLIVIER MARTY et al.

Serial No. 10/512,077 ✓

Filed: November 5, 2004

For: PROCESS FOR MODIFYING THE PROPERTIES OF A THIN LAYER AND SUBSTRATE APPLYING SAID PROCESS

INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Sir:

Applicants submit herewith the International Search Report of the corresponding PCT application, together with a Form PTO-1449 and copies of the references cited therein.

Respectfully submitted,

Ira J. Schultz  
Registration No. 28666

Form PTO-1449	ATTY DOCKET NO. 04202	APPLICATION NO. 10/512,077
INFORMATION DISCLOSURE CITATION IN AN APPLICATION		
(Use several sheets if necessary)	APPLICANT Olivier Marty et al.	
	FILING DATE November 5, 2004	GROUP

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER						DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER						DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION	
											YES	NO
	10	2	5	8	2	7	3	3/00	EP Abstract			
	2	6	8	9	9	1	2	10/93	FR w/Abstract			

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	Romanov et al, "GeSi Films With Reduced Dislocation Density Grown by Molecular-Beam Epitaxy on compliant Substrates Based on Porous Silicon" Applied Physics Letter, etc., Vol. 75, No. 26, Dec. 27, 1999, pp 4118-4120.
	Sanchez et al, "Structural and Morphological Characteristics of InGaAs/GaAs Quantum Well Structures on Tilted (111)BGaAs Grown by MBE", Journal of Crystal Growth etc., Vol. 192, No. 3-4, Sept. 1, 1998, pp 363-371.

EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.